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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	400MHz
Co-Processors/DSP	Security; SEC
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (3)
SATA	-
USB	USB 2.0 + PHY (2)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	620-BBGA Exposed Pad
Supplier Device Package	620-HBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8343ezqagd

- Address translation units for address mapping between host and peripheral
- Dual address cycle for target
- Internal configuration registers accessible from PCI
- Security engine is optimized to handle all the algorithms associated with IPSec, SSL/TLS, SRTP, IEEE Std. 802.11i®, iSCSI, and IKE processing. The security engine contains four crypto-channels, a controller, and a set of crypto execution units (EUs):
 - Public key execution unit (PKEU) :
 - RSA and Diffie-Hellman algorithms
 - Programmable field size up to 2048 bits
 - Elliptic curve cryptography
 - F2m and F(p) modes
 - Programmable field size up to 511 bits
 - Data encryption standard (DES) execution unit (DEU)
 - DES and 3DES algorithms
 - Two key (K1, K2) or three key (K1, K2, K3) for 3DES
 - ECB and CBC modes for both DES and 3DES
 - Advanced encryption standard unit (AESU)
 - Implements the Rijndael symmetric-key cipher
 - Key lengths of 128, 192, and 256 bits
 - ECB, CBC, CCM, and counter (CTR) modes
 - XOR parity generation accelerator for RAID applications
 - ARC four execution unit (AFEU)
 - Stream cipher compatible with the RC4 algorithm
 - 40- to 128-bit programmable key
 - Message digest execution unit (MDEU)
 - SHA with 160-, 224-, or 256-bit message digest
 - MD5 with 128-bit message digest
 - HMAC with either algorithm
 - Random number generator (RNG)
 - Four crypto-channels, each supporting multi-command descriptor chains
 - Static and/or dynamic assignment of crypto-execution units through an integrated controller
 - Buffer size of 256 bytes for each execution unit, with flow control for large data sizes
- Universal serial bus (USB) dual role controller
 - USB on-the-go mode with both device and host functionality
 - Complies with USB specification Rev. 2.0
 - Can operate as a stand-alone USB device
 - One upstream facing port
 - Six programmable USB endpoints

- Misaligned transfer capability
- Data chaining and direct mode
- Interrupt on completed segment and chain
- DUART
 - Two 4-wire interfaces (RxD, TxD, RTS, CTS)
 - Programming model compatible with the original 16450 UART and the PC16550D
- Serial peripheral interface (SPI) for master or slave
- General-purpose parallel I/O (GPIO)
 - 39 parallel I/O pins multiplexed on various chip interfaces
- System timers
 - Periodic interrupt timer
 - Real-time clock
 - Software watchdog timer
 - Eight general-purpose timers
- Designed to comply with IEEE Std. 1149.1™, JTAG boundary scan
- Integrated PCI bus and SDRAM clock generation

2 Electrical Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC8343EA. The device is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.

2.1 Overall DC Electrical Characteristics

This section covers the ratings, conditions, and other characteristics.

2.1.1 Absolute Maximum Ratings

Table 1 provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings¹

Parameter	Symbol	Max Value	Unit	Notes
Core supply voltage	V_{DD}	–0.3 to 1.32	V	—
PLL supply voltage	AV_{DD}	–0.3 to 1.32	V	—
DDR and DDR2 DRAM I/O voltage	GV_{DD}	–0.3 to 2.75 –0.3 to 1.98	V	—
Three-speed Ethernet I/O, MII management voltage	LV_{DD}	–0.3 to 3.63	V	—
PCI, local bus, DUART, system control and power management, I ² C, and JTAG I/O voltage	OV_{DD}	–0.3 to 3.63	V	—

Table 1. Absolute Maximum Ratings¹ (continued)

Parameter		Symbol	Max Value	Unit	Notes
Input voltage	DDR DRAM signals	MV_{IN}	-0.3 to $(GV_{DD} + 0.3)$	V	2, 5
	DDR DRAM reference	MV_{REF}	-0.3 to $(GV_{DD} + 0.3)$	V	2, 5
	Three-speed Ethernet signals	LV_{IN}	-0.3 to $(LV_{DD} + 0.3)$	V	4, 5
	Local bus, DUART, CLKIN, system control and power management, I ² C, and JTAG signals	OV_{IN}	-0.3 to $(OV_{DD} + 0.3)$	V	3, 5
	PCI	OV_{IN}	-0.3 to $(OV_{DD} + 0.3)$	V	6
Storage temperature range		T_{STG}	-55 to 150	°C	—

Notes:

- ¹ Functional and tested operating conditions are given in [Table 2](#). Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
- ² **Caution:** MV_{IN} must not exceed GV_{DD} by more than 0.3 V. This limit can be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- ³ **Caution:** OV_{IN} must not exceed OV_{DD} by more than 0.3 V. This limit can be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- ⁴ **Caution:** LV_{IN} must not exceed LV_{DD} by more than 0.3 V. This limit can be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
- ⁵ (M,L,O) V_{IN} and MV_{REF} may overshoot/undershoot to a voltage and for a maximum duration as shown in [Figure 2](#).
- ⁶ OV_{IN} on the PCI interface can overshoot/undershoot according to the PCI Electrical Specification for 3.3-V operation, as shown in [Figure 3](#).

2.1.2 Power Supply Voltage Specification

[Table 2](#) provides the recommended operating conditions for the MPC8343EA. Note that the values in [Table 2](#) are the recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Parameter	Symbol	Recommended Value	Unit	Notes
Core supply voltage	V_{DD}	$1.2\text{ V} \pm 60\text{ mV}$	V	1
PLL supply voltage	AV_{DD}	$1.2\text{ V} \pm 60\text{ mV}$	V	1
DDR and DDR2 DRAM I/O voltage	GV_{DD}	$2.5\text{ V} \pm 125\text{ mV}$ $1.8\text{ V} \pm 90\text{ mV}$	V	—
Three-speed Ethernet I/O supply voltage	LV_{DD1}	$3.3\text{ V} \pm 330\text{ mV}$ $2.5\text{ V} \pm 125\text{ mV}$	V	—
Three-speed Ethernet I/O supply voltage	LV_{DD2}	$3.3\text{ V} \pm 330\text{ mV}$ $2.5\text{ V} \pm 125\text{ mV}$	V	—

Table 19. DDR and DDR2 SDRAM Input AC Timing Specifications (continued)

At recommended operating conditions with GV_{DD} of $(1.8 \text{ or } 2.5 \text{ V}) \pm 5\%$.

Parameter	Symbol	Min	Max	Unit	Notes
266 MHz		-750	750		—
200 MHz		-750	750		—

Notes:

1. t_{CISKEW} represents the total amount of skew consumed by the controller between MDQS[n] and any corresponding bit that will be captured with MDQS[n]. This should be subtracted from the total timing budget.
2. The amount of skew that can be tolerated from MDQS to a corresponding MDQ signal is called t_{DISKEW} . This can be determined by the equation: $t_{DISKEW} = \pm (T/4 - \text{abs}(t_{CISKEW}))$; where T is the clock period and $\text{abs}(t_{CISKEW})$ is the absolute value of t_{CISKEW} .
3. This specification applies only to the DDR interface.

Figure 5 illustrates the DDR input timing diagram showing the t_{DISKEW} timing parameter.

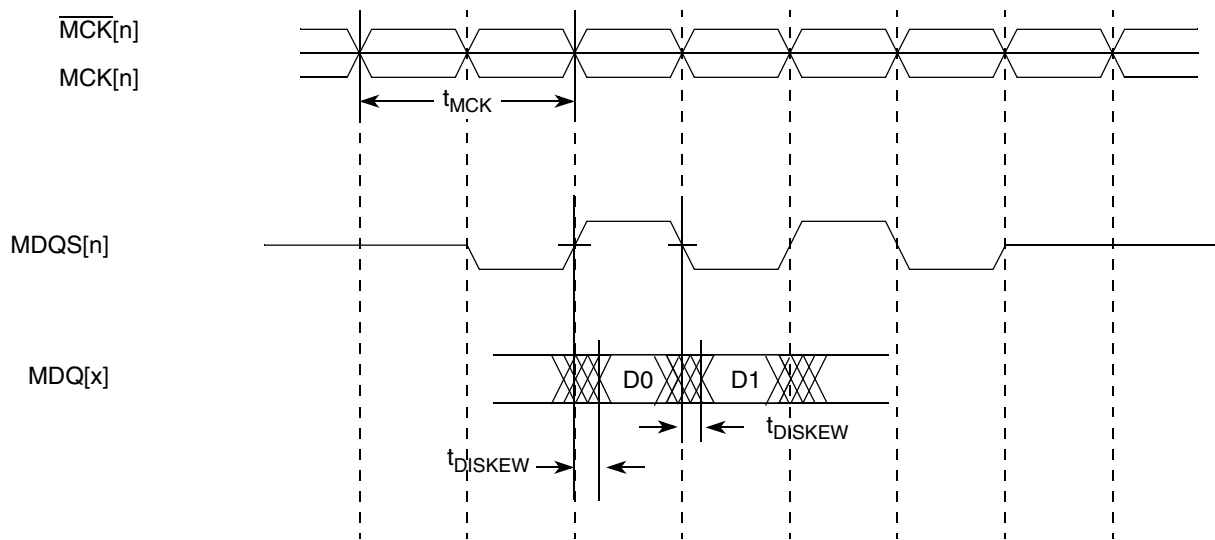


Figure 5. DDR Input Timing Diagram

6.2.2 DDR and DDR2 SDRAM Output AC Timing Specifications

Table 20 shows the DDR and DDR2 output AC timing specifications.

Table 20. DDR and DDR2 SDRAM Output AC Timing Specifications

At recommended operating conditions with GV_{DD} of $(1.8 \text{ or } 2.5 \text{ V}) \pm 5\%$.

Parameter	Symbol ¹	Min	Max	Unit	Notes
MCK[n] cycle time, (MCK[n]/MCK[n] crossing)	t_{MCK}	7.5	10	ns	2
ADDR/CMD/MODT output setup with respect to MCK	t_{DDKHAS}			ns	3
400 MHz		1.95	—		
333 MHz		2.40	—		
266 MHz		3.15	—		
200 MHz		4.20	—		

8.2.1.2 MII Receive AC Timing Specifications

Table 26 provides the MII receive AC timing specifications.

Table 26. MII Receive AC Timing Specifications

At recommended operating conditions with V_{DD}/OV_{DD} of $3.3\text{ V} \pm 10\%$.

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise (20%–80%)	t_{MRXR}	1.0	—	4.0	ns
RX_CLK clock fall time (80%–20%)	t_{MRXF}	1.0	—	4.0	ns

Note:

- The symbols for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. In general, the clock reference symbol is based on three letters representing the clock of a particular function. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 10 provides the AC test load for TSEC.

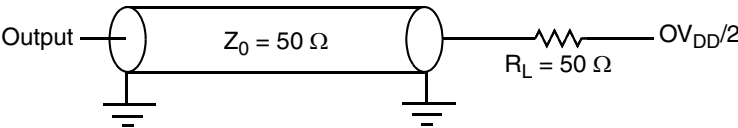


Figure 10. TSEC AC Test Load

Figure 11 shows the MII receive AC timing diagram.

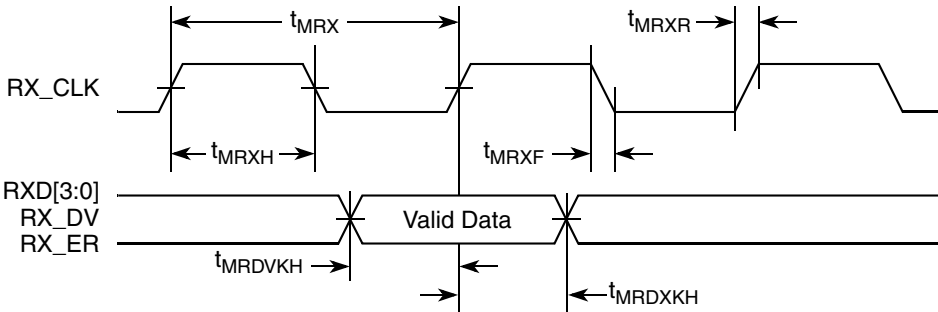


Figure 11. MII Receive AC Timing Diagram

Table 35. Local Bus General Timing Parameters—DLL Bypass⁹

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	15	—	ns	2
Input setup to local bus clock	t_{LBIVKH}	7	—	ns	3, 4
Input hold from local bus clock	t_{LBIXKH}	1.0	—	ns	3, 4
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT1}$	1.5	—	ns	5
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT2}$	3	—	ns	6
LALE output fall to LAD output transition (LATCH hold time)	$t_{LBOTOT3}$	2.5	—	ns	7
Local bus clock to output valid	t_{LBKLOV}	—	3	ns	3
Local bus clock to output high impedance for LAD/LDP	t_{LBKHOZ}	—	4	ns	8

Notes:

1. The symbols for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to the falling edge of LCLK0 (for all outputs and for \overline{LGTA} and LUPWAIT inputs) or the rising edge of LCLK0 (for all other inputs).
3. All signals are measured from $OV_{DD}/2$ of the rising/falling edge of LCLK0 to $0.4 \times OV_{DD}$ of the signal in question for 3.3 V signaling levels.
4. Input timings are measured at the pin.
5. $t_{LBOTOT1}$ should be used when RCWH[LALE] is set and when the load on the LALE output pin is at least 10 pF less than the load on the LAD output pins.
6. $t_{LBOTOT2}$ should be used when RCWH[LALE] is not set and when the load on the LALE output pin is at least 10 pF less than the load on the LAD output pins.
7. $t_{LBOTOT3}$ should be used when RCWH[LALE] is not set and when the load on the LALE output pin equals to the load on the LAD output pins.
8. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
9. DLL bypass mode is not recommended for use at frequencies above 66 MHz.

Figure 16 provides the AC test load for the local bus.

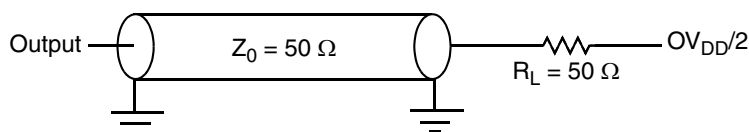

Figure 16. Local Bus C Test Load

Figure 17 through Figure 22 show the local bus signals.

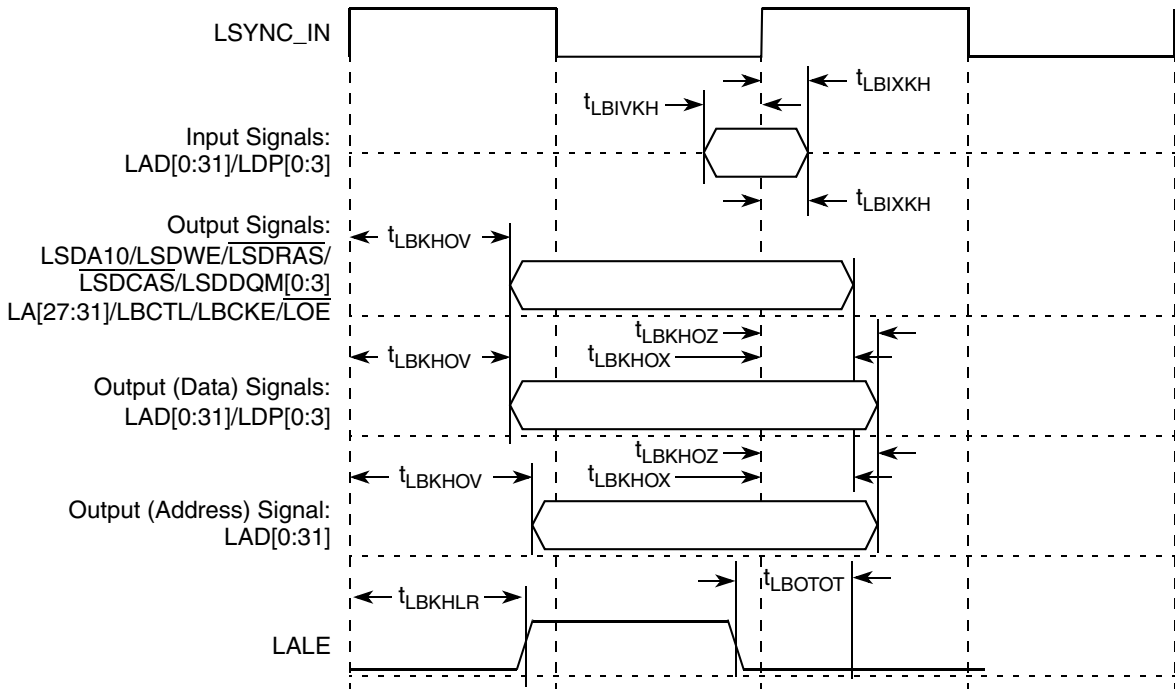


Figure 17. Local Bus Signals, Nonspecial Signals Only (DLL Enabled)

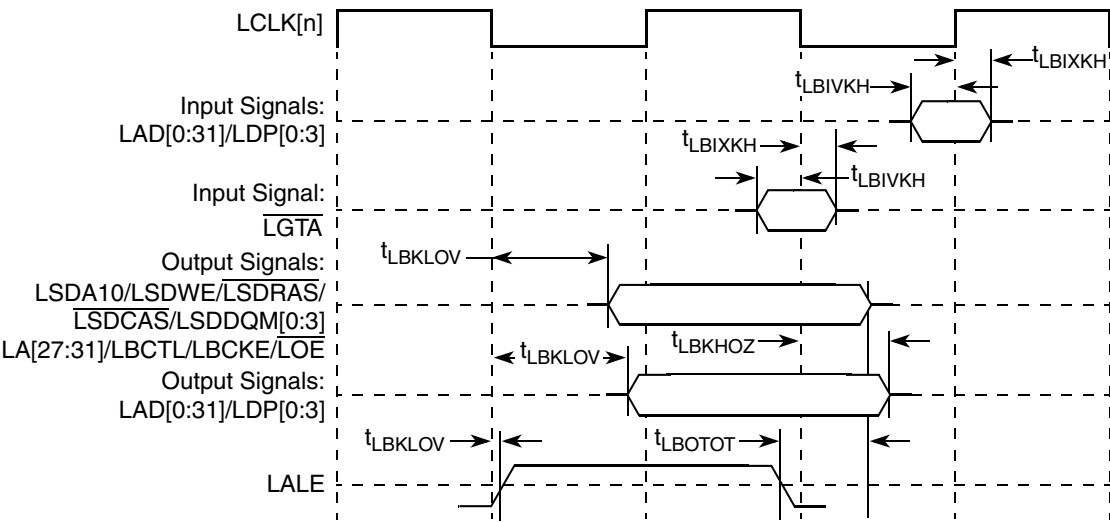


Figure 18. Local Bus Signals, Nonspecial Signals Only (DLL Bypass Mode)

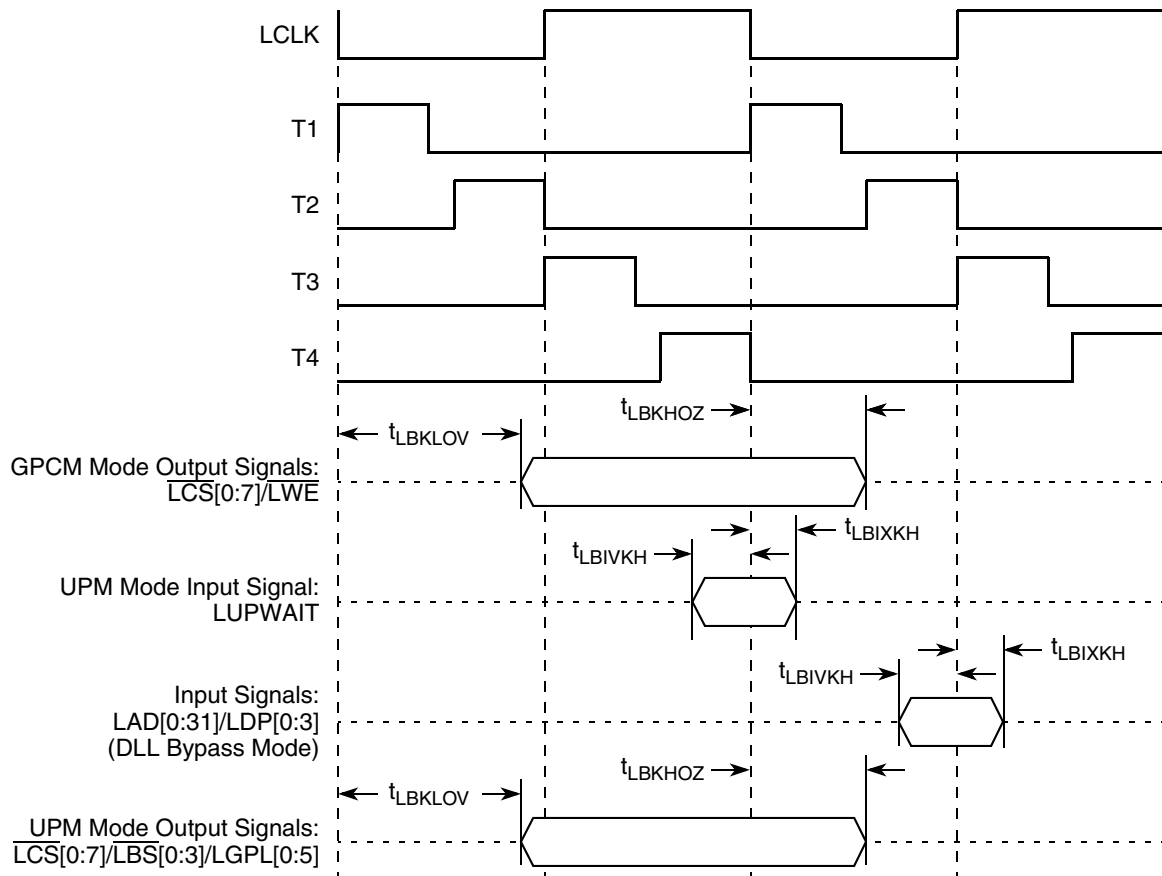


Figure 21. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (DLL Bypass Mode)

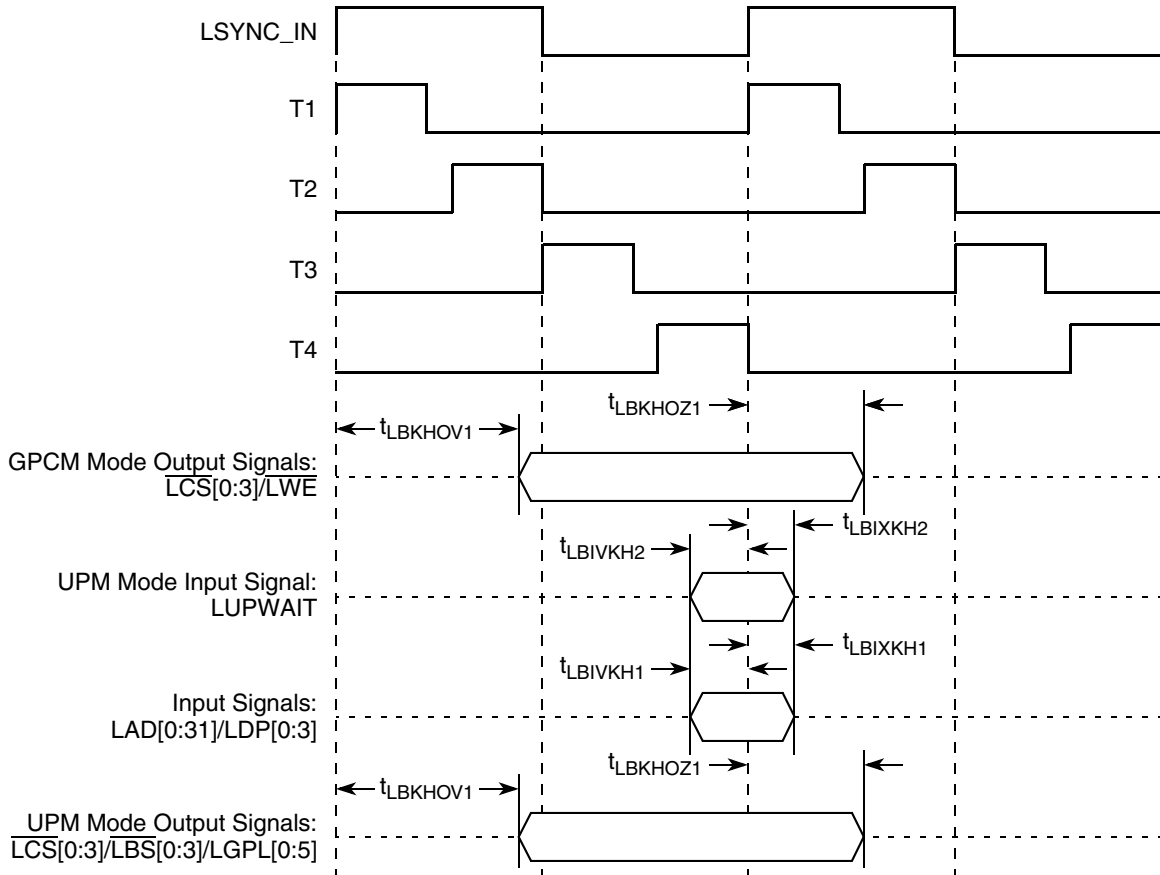


Figure 22. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 (DLL Enabled)

11 JTAG

This section describes the DC and AC electrical specifications for the IEEE Std. 1149.1 (JTAG) interface of the MPC8343EA.

11.1 JTAG DC Electrical Characteristics

Table 36 provides the DC electrical characteristics for the IEEE Std. 1149.1 (JTAG) interface of the MPC8343EA.

Table 36. JTAG Interface DC Electrical Characteristics

Parameter	Symbol	Condition	Min	Max	Unit
Input high voltage	V_{IH}	—	$OV_{DD} - 0.3$	$OV_{DD} + 0.3$	V
Input low voltage	V_{IL}	—	-0.3	0.8	V
Input current	I_{IN}	—	—	±5	μA
Output high voltage	V_{OH}	$I_{OH} = -8.0 \text{ mA}$	2.4	—	V

Figure 31 shows the PCI input AC timing diagram.

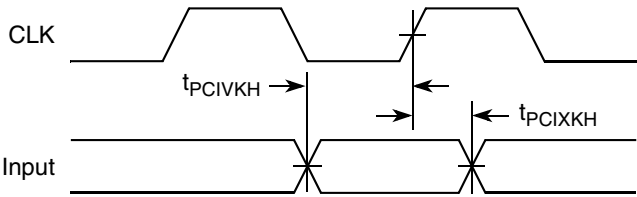


Figure 31. PCI Input AC Timing Diagram

Figure 32 shows the PCI output AC timing diagram.

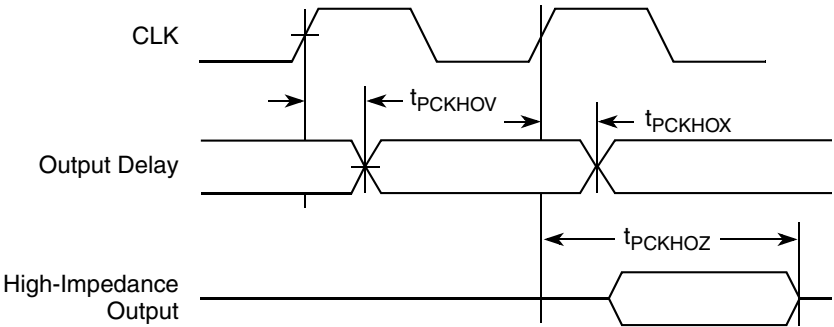


Figure 32. PCI Output AC Timing Diagram

14 Timers

This section describes the DC and AC electrical specifications for the timers.

14.1 Timer DC Electrical Characteristics

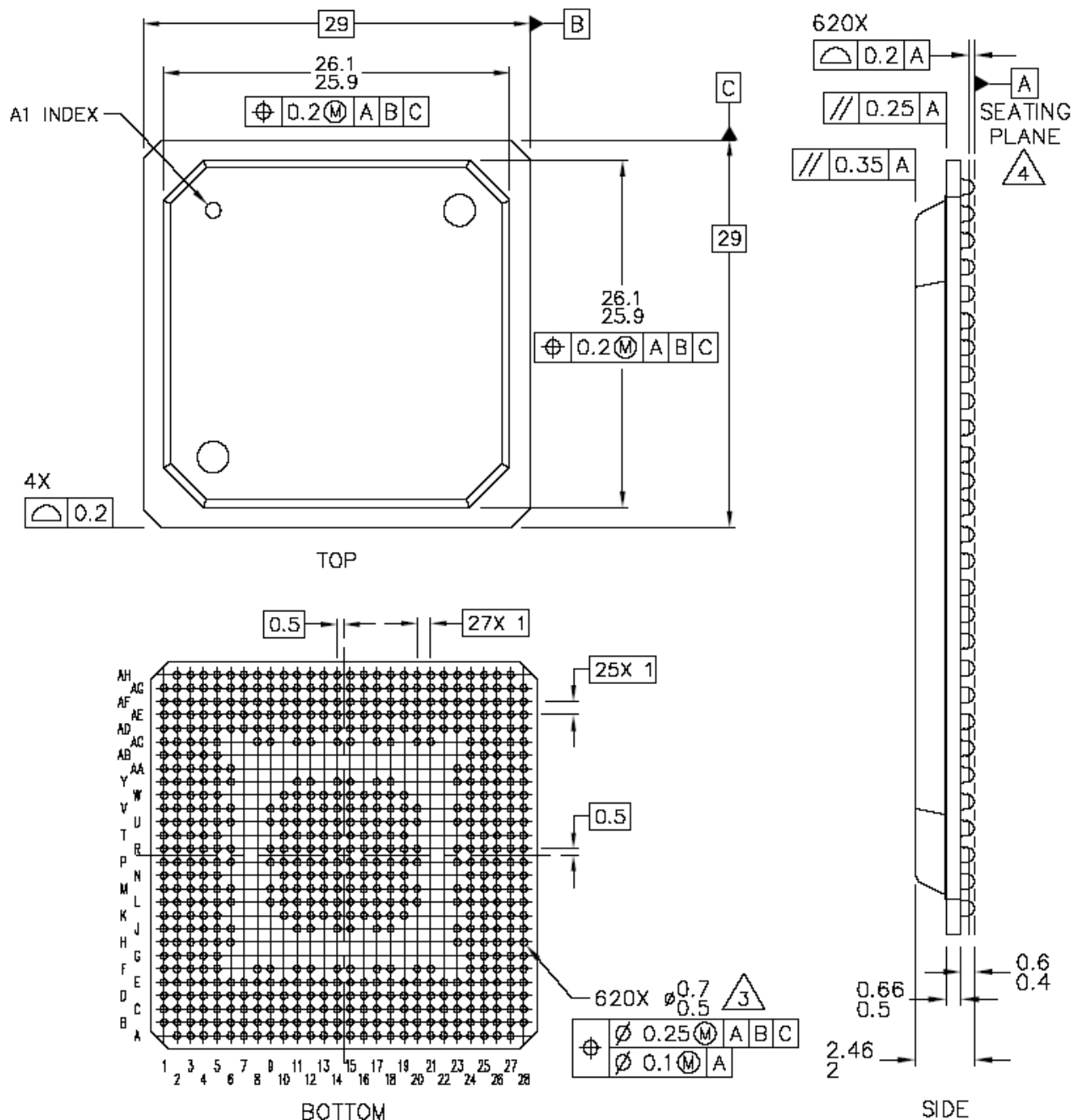
Table 43 provides the DC electrical characteristics for the MPC8343EA timer pins, including T_{IN} , \overline{TOUT} , \overline{TGATE} , and RTC_CLK .

Table 43. Timer DC Electrical Characteristics

Parameter	Symbol	Condition	Min	Max	Unit
Input high voltage	V_{IH}	—	2.0	$OV_{DD} + 0.3$	V
Input low voltage	V_{IL}	—	-0.3	0.8	V
Input current	I_{IN}	—	—	± 5	μA
Output high voltage	V_{OH}	$I_{OH} = -8.0 \text{ mA}$	2.4	—	V
Output low voltage	V_{OL}	$I_{OL} = 8.0 \text{ mA}$	—	0.5	V
Output low voltage	V_{OL}	$I_{OL} = 3.2 \text{ mA}$	—	0.4	V

18.2 Mechanical Dimensions for the MPC8343EA PBGA

Figure 36 shows the mechanical dimensions and bottom surface nomenclature for the MPC8343EA, 620-PBGA package.



Notes:

1. All dimensions are in millimeters.
2. Dimensioning and tolerancing per ASME Y14. 5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.

Figure 36. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC8343EA PBGA

18.3 Pinout Listings

Table 51 provides the pin-out listing for the MPC8343EA, 620-PBGA package.

Table 51. MPC8343EA (PBGA) Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI				
PCI1_INTA/IRQ_OUT	D20	O	OV _{DD}	2
PCI1_RESET_OUT	B21	O	OV _{DD}	—
PCI1_AD[31:0]	E19, D17, A16, A18, B17, B16, D16, B18, E17, E16, A15, C16, D15, D14, C14, A12, D12, B11, C11, E12, A10, C10, A9, E11, E10, B9, B8, D9, A8, C9, D8, C8	I/O	OV _{DD}	—
PCI1_C/ $\overline{\text{BE}}$ [3:0]	A17, A14, A11, B10	I/O	OV _{DD}	—
PCI1_PAR	D13	I/O	OV _{DD}	—
PCI1_FRAME	B14	I/O	OV _{DD}	5
PCI1_TRDY	A13	I/O	OV _{DD}	5
PCI1_IRDY	E13	I/O	OV _{DD}	5
PCI1_STOP	C13	I/O	OV _{DD}	5
PCI1_DEVSEL	B13	I/O	OV _{DD}	5
PCI1_IDSEL	C17	I	OV _{DD}	—
PCI1_SERR	C12	I/O	OV _{DD}	5
PCI1_PERR	B12	I/O	OV _{DD}	5
PCI1_REQ[0]	A21	I/O	OV _{DD}	—
PCI1_REQ[1]/CPCI1_HS_ES	C19	I	OV _{DD}	—
PCI1_REQ[2:4]	C18, A19, E20	I	OV _{DD}	—
PCI1_GNT0	B20	I/O	OV _{DD}	—
PCI1_GNT1/CPCI1_HS_LED	C20	O	OV _{DD}	—
PCI1_GNT2/CPCI1_HS_ENUM	B19	O	OV _{DD}	—
PCI1_GNT[3:4]	A20, E18	O	OV _{DD}	—
M66EN	L26	I	OV _{DD}	—
DDR SDRAM Memory Interface				
MDQ[0:31]	AC25, AD27, AD25, AH27, AE28, AD26, AD24, AF27, AF25, AF28, AH24, AG26, AE25, AG25, AH26, AH25, AG22, AH22, AE21, AD19, AE22, AF23, AE19, AG20, AG19, AD17, AE16, AF16, AF18, AG18, AH17, AH16	I/O	GV _{DD}	—

Table 51. MPC8343EA (PBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
SPI				
SPIMOSI/ $\overline{\text{LCS}}[6]$	D7	I/O	OV_{DD}	—
SPIMISO/ $\overline{\text{LCS}}[7]$	C7	I/O	OV_{DD}	—
SPICLK	B7	I/O	OV_{DD}	—
SPISEL	A7	I	OV_{DD}	—
Clocks				
PCI_CLK_OUT[0:2]	Y1, W3, W2	O	OV_{DD}	—
PCI_CLK_OUT[3]/ $\overline{\text{LCS}}[6]$	W1	O	OV_{DD}	—
PCI_CLK_OUT[4]/ $\overline{\text{LCS}}[7]$	V3	O	OV_{DD}	—
PCI_SYNC_IN/PCI_CLOCK	U4	I	OV_{DD}	—
PCI_SYNC_OUT	U5	O	OV_{DD}	3
RTC/PIT_CLOCK	E9	I	OV_{DD}	—
CLKIN	W5	I	OV_{DD}	—
JTAG				
TCK	H27	I	OV_{DD}	—
TDI	H28	I	OV_{DD}	4
TDO	M24	O	OV_{DD}	3
TMS	J27	I	OV_{DD}	4
$\overline{\text{TRST}}$	K26	I	OV_{DD}	4
Test				
TEST	F28	I	OV_{DD}	6
TEST_SEL	T3	I	OV_{DD}	7
PMC				
$\overline{\text{QUIESCE}}$	K27	O	OV_{DD}	—
System Control				
$\overline{\text{PORESET}}$	K28	I	OV_{DD}	—
$\overline{\text{HRESET}}$	M25	I/O	OV_{DD}	1
$\overline{\text{SRESET}}$	L27	I/O	OV_{DD}	2
Thermal Management				
THERM0	B15	I	—	8

Table 51. MPC8343EA (PBGA) Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
OV _{DD}	B27, D3, D11, D19, E15, E23, F5, F8, F11, F14, F17, F20, G24, H23, H24, J6, J14, J17, J18, K4, L9, L20, L23, L25, M6, M9, M20, P5, P20, P23, R6, R9, R24, U23, V4, V6	PCI, 10/100 Ethernet, and other standard (3.3 V)	OV _{DD}	—
MVREF1	AF19	I	DDR reference voltage	—
MVREF2	AE10	I	DDR reference voltage	—
No Connection				
NC	A22, A23, A24, B22, B23, B24, C21, C22, C23, C24, D21, D22, D23, D24, E21, M27, M28, N26, N27, N28, P25, P26, P27, R28, T24, T25, T26, T27, T28, U27, U28, Y3, Y4, Y5, AA1, AA2, AA3, AA4, AB1, AB2, AB3, AB4, AC1, AC2, AC3, AC4, AD1, AD2, AD3, AD5, AD7, AD11, AD12, AE4, AE6, AE8, AE9, AE23, AF1, AF5, AF6, AF8, AF24, AG1, AG3, AG4, AG7, AG8, AG9, AG10, AH2, AH3, AH5, AH8, AH9, V5, V2, V1	—	—	—

Notes:

1. This pin is an open-drain signal. A weak pull-up resistor (1 k Ω) should be placed on this pin to OV_{DD}.
2. This pin is an open-drain signal. A weak pull-up resistor (2–10 k Ω) should be placed on this pin to OV_{DD}.
3. During reset, this output is actively driven rather than three-stated.
4. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
5. This pin should have a weak pull-up if the chip is in PCI host mode. Follow the PCI specifications.
6. This pin must be always be tied to GND.
7. This pin must always be pulled up to OV_{DD}.
8. Thermal sensitive resistor.
9. It is recommended that MDIC0 be tied to GND using an 18.2 Ω resistor and MDIC1 be tied to DDR power using an 18.2 Ω resistor.
10. TSEC1_TXD[3] is required an external pull-up resistor. For proper functionality of the device, this pin must be pulled up or actively driven high during a hard reset. No external pull-down resistors are allowed to be attached to this net.
11. A weak pull-up resistor (2–10 k Ω) should be placed on this pin to LV_{DD1}.
12. For systems that boot from local bus (GPCM)-controlled NOR flash, a pull up on LGPL4 is required.

Figure 37 shows the internal distribution of the clocks.



The primary clock source can be one of two inputs, CLKIN or PCI_CLK, depending on whether the device is configured in PCI host or PCI agent mode. When the MPC8343EA is configured as a PCI host device, CLKIN is its primary input clock. CLKIN feeds the PCI clock divider ($\div 2$) and the multiplexors for PCI_SYNC_OUT and PCI_CLK_OUT. The CFG_CLKIN_DIV configuration input selects whether CLKIN or CLKIN/2 is driven out on the PCI_SYNC_OUT signal. The OCCR[PCICDn] parameters select whether CLKIN or CLKIN/2 is driven out on the PCI_CLK_OUTn signals.

PCI_SYNC_OUT is connected externally to PCI_SYNC_IN to allow the internal clock subsystem to synchronize to the system PCI clocks. PCI_SYNC_OUT must be connected properly to PCI_SYNC_IN, with equal delay to all PCI agent devices in the system, to allow the MPC8343EA to function. When the device is configured as a PCI agent device, PCI_CLK is the primary input clock and the CLKIN signal should be tied to GND.

Table 53 provides the operating frequencies for the MPC8343EA PBGA under recommended operating conditions.

Table 53. Operating Frequencies for PBGA

Parameter ¹	266 MHz	333 MHz	400 MHz	Unit
e300 core frequency (<i>core_clk</i>)	200–266	200–333	200–400	MHz
Coherent system bus frequency (<i>csb_clk</i>)	100–266			MHz
DDR1 memory bus frequency (MCK) ²	100–133			MHz
DDR2 memory bus frequency (MCK) ³	100–133			MHz
Local bus frequency (LCLK _n) ⁴	16.67–133			MHz
PCI input frequency (CLKIN or PCI_CLK)	25–66			MHz
Security core maximum internal operating frequency	133			MHz
USB_DR, USB_MPH maximum internal operating frequency	133			MHz

¹ The CLKIN frequency, RCWL[SPMF], and RCWL[COREPLL] settings must be chosen so that the resulting *csb_clk*, MCLK, LCLK[0:2], and *core_clk* frequencies do not exceed their respective maximum or minimum operating frequencies. The value of SCCR[ENCCM], SCCR[USBDRCM], and SCCR[USBMPHCM] must be programmed so that the maximum internal operating frequency of the Security core and USB modules does not exceed the respective values listed in this table.

² The DDR data rate is 2× the DDR memory bus frequency.

³ The DDR data rate is 2× the DDR memory bus frequency.

⁴ The local bus frequency is ½, ¼, or 1/8 of the *lbiu_clk* frequency (depending on LCCR[CLKDIV]) which is in turn 1× or 2× the *csb_clk* frequency (depending on RCWL[LBIUCM]).

19.1 System PLL Configuration

The system PLL is controlled by the RCWL[SPMF] parameter. Table 54 shows the multiplication factor encodings for the system PLL.

Table 54. System PLL Multiplication Factors

RCWL[SPMF]	System PLL Multiplication Factor
0000	× 16
0001	Reserved
0010	× 2
0011	× 3
0100	× 4
0101	× 5
0110	× 6
0111	× 7
1000	× 8
1001	× 9
1010	× 10

Table 54. System PLL Multiplication Factors (continued)

RCWL[SPMF]	System PLL Multiplication Factor
1011	× 11
1100	× 12
1101	× 13
1110	× 14
1111	× 15

As described in [Section 19, “Clocking,”](#) the LBIUCM, DDRCM, and SPMF parameters in the reset configuration word low and the CFG_CLKIN_DIV configuration input signal select the ratio between the primary clock input (CLKIN or PCI_CLK) and the internal coherent system bus clock (*csb_clk*). [Table 55](#) and [Table 56](#) show the expected frequency values for the CSB frequency for select *csb_clk* to CLKIN/PCI_SYNC_IN ratios.

Table 55. CSB Frequency Options for Host Mode

CFG_CLKIN_DIV at Reset ¹	SPMF	csb_clk : Input Clock Ratio ²	Input Clock Frequency (MHz) ²			
			16.67	25	33.33	66.67
			csb_clk Frequency (MHz)			
Low	0010	2 : 1				133
Low	0011	3 : 1				200
Low	0100	4 : 1				266
Low	0101	5 : 1				333
Low	0110	6 : 1	100	150	200	
Low	0111	7 : 1	116	175	233	
Low	1000	8 : 1	133	200	266	
Low	1001	9 : 1	150	225	300	
Low	1010	10 : 1	166	250	333	
Low	1011	11 : 1	183	275		
Low	1100	12 : 1	200	300		
Low	1101	13 : 1	216	325		
Low	1110	14 : 1	233			
Low	1111	15 : 1	250			
Low	0000	16 : 1	266			

The junction-to-ambient thermal resistance is an industry-standard value that provides a quick and easy estimation of thermal performance. Generally, the value obtained on a single-layer board is appropriate for a tightly packed printed-circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated. Test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

20.2.2 Estimation of Junction Temperature with Junction-to-Board Thermal Resistance

The thermal performance of a device cannot be adequately predicted from the junction-to-ambient thermal resistance. The thermal performance of any component is strongly dependent on the power dissipation of surrounding components. In addition, the ambient temperature varies widely within the application. For many natural convection and especially closed box applications, the board temperature at the perimeter (edge) of the package is approximately the same as the local air temperature near the device. Specifying the local ambient conditions explicitly as the board temperature provides a more precise description of the local ambient conditions that determine the temperature of the device.

At a known board temperature, the junction temperature is estimated using the following equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_J = junction temperature (°C)

T_A = ambient temperature for the package (°C)

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

P_D = power dissipation in the package (W)

When the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. The application board should be similar to the thermal test condition: the component is soldered to a board with internal planes.

20.2.3 Experimental Determination of Junction Temperature

To determine the junction temperature of the device in the application after prototypes are available, use the thermal characterization parameter (Ψ_{JT}) to determine the junction temperature and a measure of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

T_J = junction temperature (°C)

T_T = thermocouple temperature on top of package (°C)

Ψ_{JT} = junction-to-ambient thermal resistance (°C/W)

P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per the JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so

$R_{\theta JC}$ = junction-to-case thermal resistance ($^{\circ}\text{C}/\text{W}$)

P_D = power dissipation (W)

21 System Design Information

This section provides electrical and thermal design recommendations for successful application of the MPC8343EA.

21.1 System Clocking

The MPC8343EA includes two PLLs:

1. The platform PLL generates the platform clock from the externally supplied CLKIN input. The frequency ratio between the platform and CLKIN is selected using the platform PLL ratio configuration bits as described in [Section 19.1, “System PLL Configuration.”](#)
2. The e300 core PLL generates the core clock as a slave to the platform clock. The frequency ratio between the e300 core clock and the platform clock is selected using the e300 PLL ratio configuration bits as described in [Section 19.2, “Core PLL Configuration.”](#)

21.2 PLL Power Supply Filtering

Each PLL gets power through independent power supply pins (AV_{DD1} , AV_{DD2} , respectively). The AV_{DD} level should always equal to V_{DD} , and preferably these voltages are derived directly from V_{DD} through a low frequency filter scheme.

There are a number of ways to provide power reliably to the PLLs, but the recommended solution is to provide four independent filter circuits as illustrated in [Figure 38](#), one to each of the four AV_{DD} pins. Independent filters to each PLL reduce the opportunity to cause noise injection from one PLL to the other.

The circuit filters noise in the PLL resonant frequency range from 500 kHz to 10 MHz. It should be built with surface mount capacitors with minimum effective series inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

To minimize noise coupled from nearby circuits, each circuit should be placed as closely as possible to the specific AV_{DD} pin being supplied. It should be possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of package, without the inductance of vias.

[Figure 38](#) shows the PLL power supply filter circuit.

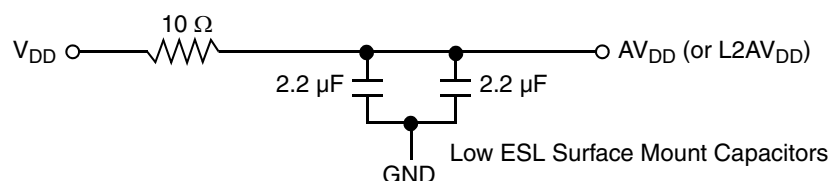


Figure 38. PLL Power Supply Filter Circuit

However, while $\overline{\text{HRESET}}$ is asserted, these pins are treated as inputs, and the value on these pins is latched when $\overline{\text{PORESET}}$ deasserts. Then the input receiver is disabled and the I/O circuit takes on its normal function. Careful board layout with stubless connections to these pull-up/pull-down resistors coupled with the large value of the pull-up/pull-down resistor should minimize the disruption of signal quality or speed for the output pins.

21.7 Pull-Up Resistor Requirements

The MPC8343EA requires high resistance pull-up resistors (10 k Ω is recommended) on open-drain pins, including I²C pins, and IPIC interrupt pins.

For more information on required pull-up resistors and the connections required for the JTAG interface, refer to application note AN2931, “PowerQUICC Design Checklist.”

22 Ordering Information

This section presents ordering information for the device discussed in this document, and it shows an example of how the parts are marked.

NOTE

The information in this document is accurate for revision 3.x silicon and later (in other words, for orderable part numbers ending in A or B). For information on revision 1.1 silicon and earlier versions, see the *MPC8343E PowerQUICC II Pro Integrated Host Processor Hardware Specifications* (Document Order No. MPC8343EEC).

22.1 Part Numbers Fully Addressed by This Document

Table 62 shows an analysis of the Freescale part numbering nomenclature for the MPC8343EA. The individual part numbers correspond to a maximum processor core frequency. Each part number also contains a revision code that refers to the die mask revision number. For available frequency configuration